Some recent results on local testing of sparse linear codes

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Locally Testable Codes

- Let C \subset F_2 ^N be a linear code.
- **C** is *locally testable* if there is a **tester T** such that :
	- Given oracle access to $r \in F_2^N$
	- **T** queries **r** in few locations
		- If $r \in C$, then **Accept**

r

• If r is ϵ -far from C, then Reject

The Hadamard Code

Linearity Testing of Boolean Functions

Given oracle access to

Test using few queries if **f** is linear.

- If f **is linear**, **Accept**
- If f is ϵ -**far** from all g that are linear, **Reject**

 $\Pr_{\mathbf{x}}[\mathbf{f}(\mathbf{x}) \neq \mathbf{g}(\mathbf{x})] > \epsilon$

BLR Linearity Test

- Choose x, y uniformly at random
- Query $f(x)$, $f(y)$ and $f(x+y)$
	- Check if
		- If **Yes***,* then *Accept.*
		- If **No,** then *Reject*

$$
\frac{?}{f(x) + f(y)} = f(x+y)
$$

Theorem [BLR '90]:

Hadamard Code is locally testable

- If f **is linear**, then test *accepts* with probability 1.
- $-$ If f is ϵ -far (under the uniform distribution) from being linear, test *rejects* with probability $> \epsilon_0 > 0$

Talk Overview

• Locally testable codes < Testing linearity under some distribution μ

• Criterion for testing under μ

• Local List Decoding and Testing with high error

- Time Complexity
	- Dual BCH codes
	- connections to the noisy parity problem

Testing Linearity under General Distributions

• Given

f

- $-$ a distribution π_{L} over $\text{F}_\text{2}^{\text{n}}$
	- μ distance $(g,h) = Pr_{x \in \mu} [g(x) \neq h(x)]$
- $-$ Oracle access to **f : F₂ⁿ → F₂**

A Goal: If f *is linear, Accept* If f is *efar* from all linear functions in *u* distance, Reject

 F_2^n

 μ

A 3 query

test actually

works for all

distributions!

[HK07]

An odd consequence

Goal: If f *is linear, Accept* If f is *efar* from all linear functions in *u* distance, Reject

The tester should make queries essentially according to μ

Stronger Goal: With high probability, accept functions that are close to linear "**Tolerant property testing**" [PRR]

Tolerant Linearity Testing

- Given
	- $-$ a distribution μ over $F_2^{\ n}$
	- $-$ Oracle access to $f : F_2$ ⁿ \rightarrow F_2
- If f is *close* to linear in μ -distance, then Accept with high probability
- \cdot If f is *far* from linear in μ -distance, then **Reject** with noticeable probability

The BLR Linearity Tester is a Tolerant Tester for Un

Connection to Locally Testable Codes

• For every **linear code C**, there is a distribution μ such that

– C is locally testable linearity is **tolerantly**

testable under μ .

Uniform distribution on the columns of the generator matrix for C

• *Tolerance crucial*

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Need for correlation

- Say the test queries x_1 , ..., x_k
- Each query $x_i \in F_2$ ⁿ essentially according to μ

- x_i's should satisfy some linear relation
- *A bare minimum for testing:* – The existence of such a correlated distribution*.*

Uniform Correlatability

• Definition: *µ* is **k-uniformly correlatable** if

there exists a joint distribution

$$
\begin{array}{|c|c|c|c|}\n \hline\n X_1 & X_2 & \dots & X_k\n \end{array}\n \qquad\n \begin{array}{|c|c|c|}\n \hline\n \sum X_i = X\n \end{array}
$$

$$
\sum X_i = X
$$

- 1. Each X_i is distributed as μ
- 2. $X = \sum X_i$ is distributed uniformly

Let $\mu^{(k)}$ denote this joint distribution

Theorem

If μ is k-uniformly correlatable, then **linearity is tolerantly testable under** μ **in O(k) queries**

Holds for tolerantly testing homomorphisms between any two abelian groups (under general distributions).

Tolerantly testable distributions

- Corollary: Linearity is tolerantly testable with a constant number of queries under:
	- 1. Product distributions
	- 2. Symmetric distributions supported on words of weight \in [γ n, (1- γ) n]
	- 3. Low Fourier-bias distributions
		- e.g. uniform distribution over a large random subset
			- "Sparse random linear codes are locally testable" [KS07]
			- Generalizes [KS07] to arbitrary groups

Theorem:

- **If** $C \subseteq \{0,1\}^N$ **is a linear code which is** 1. **Sparse:** $|C| \le N^c$
- **2. "unbiased": Each nonzero codeword has** $\mathsf{weight} \in \mathbf{(1/2 - N^{-\gamma}, \ \frac{1}{2} + N^{-\gamma})}$
- **Then C is locally testable with constantly many queries.**

Proof that Uniform Correlatability testability

Recall:

Given distribution μ that is **k-uniformly correlatable**.

There exists Such that

- 1. Each X_i is distributed as μ
- 2. $X = \sum X_i$ is distributed uniformly over F_2 ⁿ
- Let $\boldsymbol{\mu}^{(\mathsf{k})}$ denote the joint distribution (X₁, ..., X_k)
- Let $\mu^{(k)} | \sum x_i = x$ denote the joint distribution of $(X_1, ..., X_k)$ conditioned on ΣX **i = X**
- Let U_n denote the **uniform distribution on F**₂ⁿ

Rough idea

• Use $\mu^{(k)}$ to generate *correlated queries* satisfying *linear relations*.

• 2 carefully designed tests: **Test 1** and **Test 2**

TEST 1

- Sample X and Y indep. from **Uⁿ** . Let Z = X+Y
- Sample $(X_1, ..., X_k)$ from $\boldsymbol{\mu^{(k)}}$ $|\Sigma X_i| = X$ $(Y_1, ..., Y_k)$ from $\mu^{(k)} | \Sigma Y_i = Y$ and (Z₁, $...$, Z_k) from $\boldsymbol{\mu^{(k)}}$ | $\sum z_i$ = Z

Check if $\sum f(X_i) + \sum f(Y_i) = \sum f(Z_i)$ **in spirit: the BLR test!**

Rewriting Test 1

- Defn: Let $h(X) = f(X_1) + \cdots + f(X_k)$, where $(X_1, ..., X_k) \in \mu^{(k)} | \sum X_i = X$
- h is a *probabilistic function*.
- Test 1 rewritten: Sample X, Y from U_n . Let Z=X+Y. Check: $h(X) + h(Y) = h(Z)$ The BLR test!

Test 1 passes whp \Rightarrow A related function *h* is close to a *linear function g* under the *uniform distribution*

TEST 2

• Sample Z from μ . Sample X, Y from U_n such that $X+Y = Z$

• Sample $(X_1, ..., X_k)$ from $\boldsymbol{\mu^{(k)}} | \Sigma X_i = X$ and $(Y_1, ..., Y_k)$ from $\boldsymbol{\mu^{(k)}} | \sum Y_i = Y_i$

Check if $\sum f(X_i) + \sum f(Y_i) = f(Z)$

Understanding Test 2

Assume Test 1 passes whp. So h \approx linear g. *Want to show:* **for** $Z \in \mu$ **,** $f(Z) \approx g(Z)$

If Test 2 passes, $f(Z) \approx \sum f(X_i) + \sum f(Y_i)$

But by defn of h, $\sum f(X_i) + \sum f(Y_i) = h(X) + h(Y)$

Since Test 1 passes, $h(X) + h(Y) \approx g(X) + g(Y)$

Since g is linear $g(X) + g(Y) = g(Z)$

Test 1 passes whp \Rightarrow A related function *h* is close to *a linear function g* under the *uniform distribution*

If Test 2 also passes whp \Rightarrow *f* is close to *the linear function g* under the ^¹ *Distribution*

To summarize

• "Extend" f defined on μ to h defined on F_2 ⁿ – uniform-correlatability

• Test if h is close to a linear function g under U_{n} – the BLR test

• Test if f is close to g under μ

Some Questions

• What distributions are correlatable?

• Under what distributions is linearity testable?

• Are all* sparse linear codes are locally testable?

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• Criterion for tolerant testing under μ

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- Time Complexity
	- Dual BCH codes
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The *high error* regime

Recall: for **Local testability:**

If $r \in C$, then **Accept** (with prob 1),

If r is ϵ -far from C, then Reject (with noticable probability)

In the **high error regime:** If Δ (**r, C**) < $\frac{1}{2}$ - ϵ , then **Accept** If Δ (**r, C**) \approx $\frac{1}{2}$, then **Reject**

Distance estimation:

For $0 < \epsilon_2 < \epsilon_1 < \frac{1}{2}$, If $\Delta(\mathsf{r},\mathsf{C}) < \mathcal{V}_2$ - ϵ_{n} , then Accept If Δ (**r, C**) > $\frac{1}{2}$ - ϵ ₂, then **Reject**

Theorem:

- **If** $C \subset \{0,1\}^N$ **is a linear code which is**
- **1. Sparse:** $|C| \leq N^c$
- **2. "unbiased": Each nonzero codeword has weight** \in (1/2- N⁻^{γ}, $\frac{1}{2}$ + N^{- γ})

Then C is locally testable and locally list decodable from $\frac{1}{2}$ - ϵ fraction errors using only $poly(1/\epsilon)$ queries.

Corollary:

Random sparse linear codes are locally testable and locally list decodable with $\frac{1}{2}$ - ϵ fraction errors using only poly(1/ ϵ) **queries.**

Dual BCH codes are locally testable and locally list decodable with $\frac{1}{2} - \epsilon$ **fraction** errors using only $poly(1/\epsilon)$ queries.

Proof

Reduce to the Hadamard Code!

The Hadamard code

- **[BCHKS'96]:** Fourier analysis proof of BLR Test – Hadamard Code is testable in the high error regime
- **[GL'89]:** Hadamard Code is locally list decodable up to $1/2$ - ϵ fraction errors with **poly(1/** ϵ) queries.
- **Distance estimation:** For $0 < \epsilon_2 < \epsilon_1 < \frac{1}{2}$, In poly(1/ ϵ_1 - ϵ_2) queries, can distinguish between
	- 1. $(1/2 \epsilon_1)$ close to a codeword
	- 2. $(1/2 \epsilon_2)$ far from every codeword

Recall: Low error testing

• "Extend" f defined on μ to h defined on F_2 ⁿ – uniform-correlatability

• Test if h is close to a linear function g under U_{n} – the BLR test

• Test if f is close to g under μ

Recall: *from f to h* - Uniform Correlatability

of f from closeness of h

Independent uniform correlatability

- C: Sparse, unbiased code
- S: Set of columns of generator matrix
	- $-$ S is a large set ($|S| \approx 2^{n/k}$) with small Fourier bias **(**¼ **2 -n/10k).**

Extending f to all of F_2 ⁿ

Defn: Let $h(X) = f(X_1) + \cdots + f(X_k)$, **where X**_i are sampled independently from μ | Σ X_i = X

 $\text{Defn: Let } \text{Corr}_{\mu} (\textbf{f}, \textbf{g}) = 1 - 2 \Delta_{\mu} (\textbf{f}, \textbf{g})$

 $\textsf{Corr}_{\textsf{U}}\left(\textsf{h},\textsf{g}\right) \approx \textsf{Corr}_{\left.\textsf{x}\right. \in \mu\left(\textsf{k}\right)}\left(\textsf{h}(\textsf{X}),\textsf{g}(\textsf{X})\right)$ $=$ Corr $\mathbf{x}_{1,\dots,\mathbf{x}}\mathbf{k}\in\mu(\mathbf{f}(\mathbf{X}_1)+\dots+\mathbf{f}(\mathbf{X}_k), \mathbf{g}(\mathbf{X}_1)+\dots+\mathbf{g}(\mathbf{X}_k))$ **= [Corr**^¹ **(f,g)]k**

• If $\Delta_{\mu}^{}$ (f,g) = (1 - α)/2 , then $\Delta_{Un}^{}$ (h,g) \approx (1 - α^{k})/2

Getting oracle access to h

Recall: $h(X) = f(X_1) + \cdots + f(X_k)$,

where X_i are sampled independently from μ **|** Σ **X_i = X**

Given oracle access to f, can simulate oracle access to h.

From f to h

- Given oracle access to **f**, can simulate oracle access to the *extended function* **h.**
- $\Delta_{\text{Un}}(\textsf{h}, \textsf{L})$ essentially captures $\Delta_{\mu}(\textsf{f}, \textsf{L})$
- We understand testing over U_n very well.
- **We can** *transfer* **questions of list decoding, testing, distance estimation over** μ **to those over Un.**

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Time Complexity

Recall: $h(X) = f(X_1) + \cdots + f(X_k)$

where X_i are sampled independently from μ | Σ X_i = X

• **Need to** *"Back Sample".*

In general (for a random set S) could take time poly(|S|).

Dual-BCH Codes

• The set $S \subseteq F_2$ ⁿ is structured.

 $-$ [KL05]: For $X \in F_2^n$ can efficiently compute (in time **polylog (|S|)**) which k-subsets of S sum to X.

Time complexity: decoding a random linear code

Theorem:

If $C \subseteq \{0,1\}^N$ is a linear code of bias = $N^{-\gamma}$ then C is list decodable with $\frac{1}{2} - \epsilon$ **fraction errors in time exp(n/loglog n)**

Proof: Reduce to the Hadamard code!

[BKW03, Ly05]: Learning noisy parities:

The Hadamard code can be decoded from random samples from a received word (**a code word corrupted with random errors**) in time exp(n/log n)

[FGKP06]: Agnostically learning parities:

The Hadamard code can be list decoded from random samples from a received word in time exp(n/log n)

Main features

- Need to take super-constantly many sums of S to get to Hadamard
	- Noise rate gets very high
- **Getting random samples from h is easy** given access to random samples from f.
	- Back sampling not needed.

Thank you!